



## **SRD1000 Superconductive Reference Devices**

**Reporting period: mid-2002 - December 2003**

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Wim Bosch, HDL, Leiden, The Netherlands

[HDLinfo@xs4all.nl](mailto:HDLinfo@xs4all.nl)

[www.xs4all.nl/~hdleiden/srd1000](http://www.xs4all.nl/~hdleiden/srd1000)



## **SRD1000 Superconductive Reference Devices**

### **Development**

HDL

LION-KOL

NMi-VSL

UT

### **Evaluation**

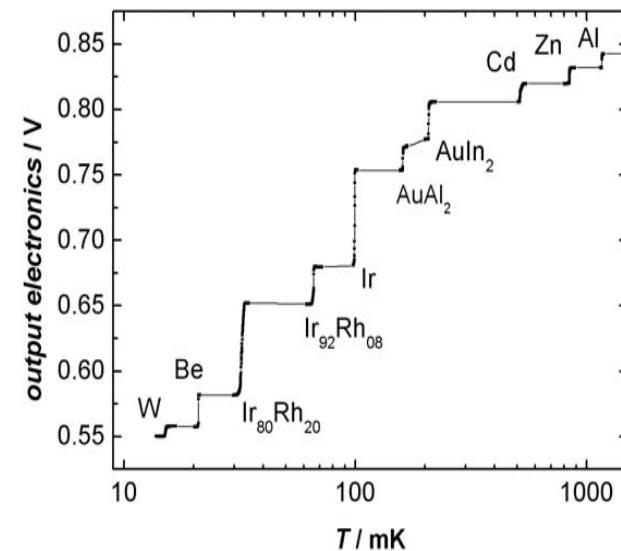
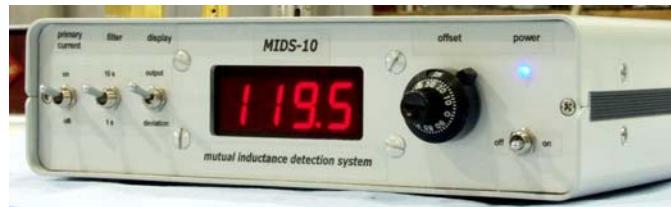
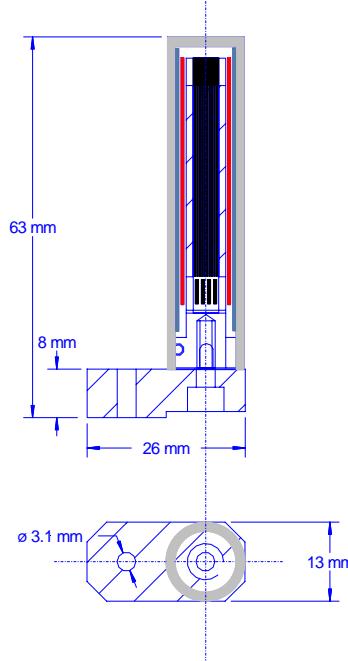
BNM-INM

PTB

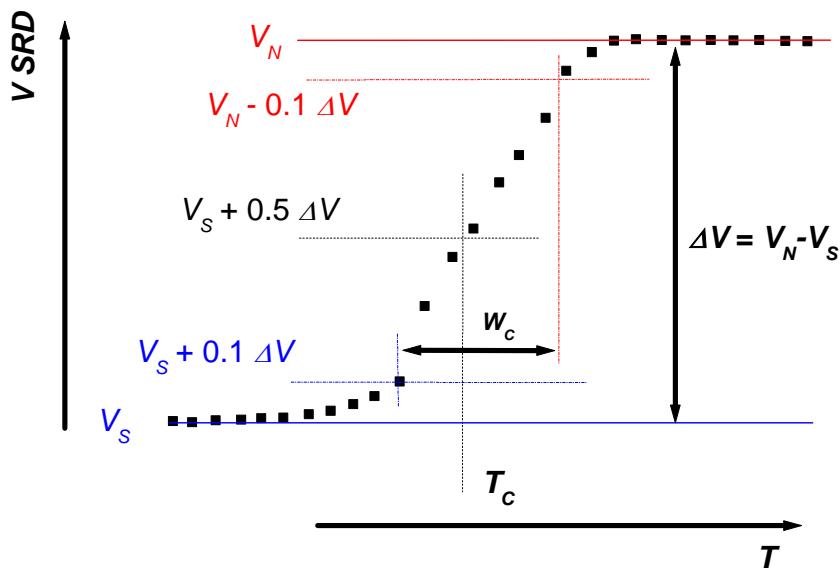
NPL

CNRS / AL

# SRD1000 introduction



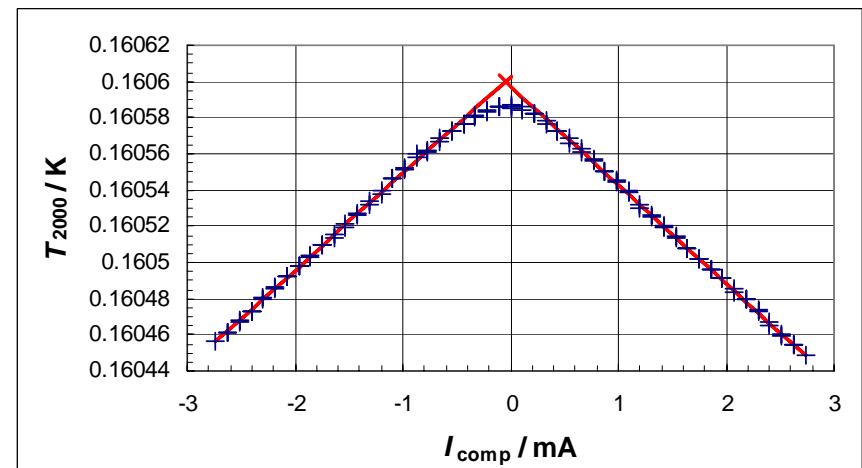
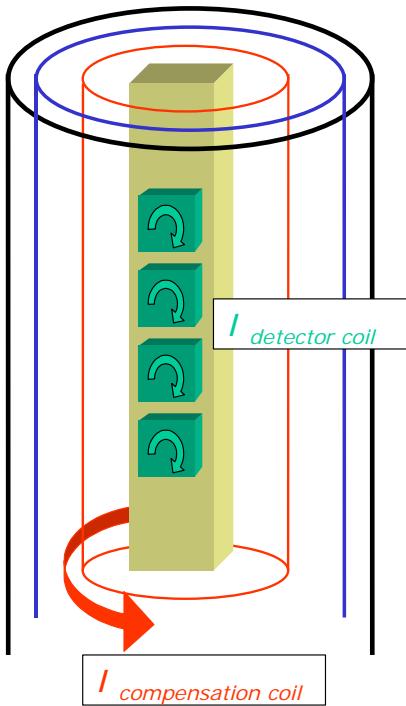
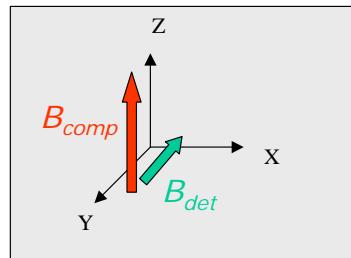
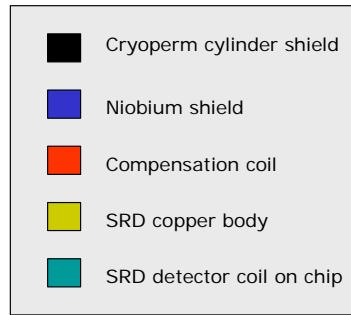
# SRD1000 introduction



#	material	$T_c$	$W_c$	uncert
		[mK]	[mK]	[%]
1	W	15	0.2	0.9
2	Be	21.98	0.08	0.5
3	Ir <sub>80</sub> Rh <sub>20</sub>	32.32	0.99	0.4
4	Ir <sub>92</sub> Rh <sub>08</sub>	66.1	0.94	0.2
5	Ir	99.34	0.55	0.1
6	AuAl <sub>2</sub>	160.89	0.73	0.2
7	AuIn <sub>2</sub>	207.80	1.56	0.2
8	Cd	516.9	14	0.2
9	Zn	843.7	5.9	0.1
10	Al	1166	4.0	<0.1

(values found for SRD004)

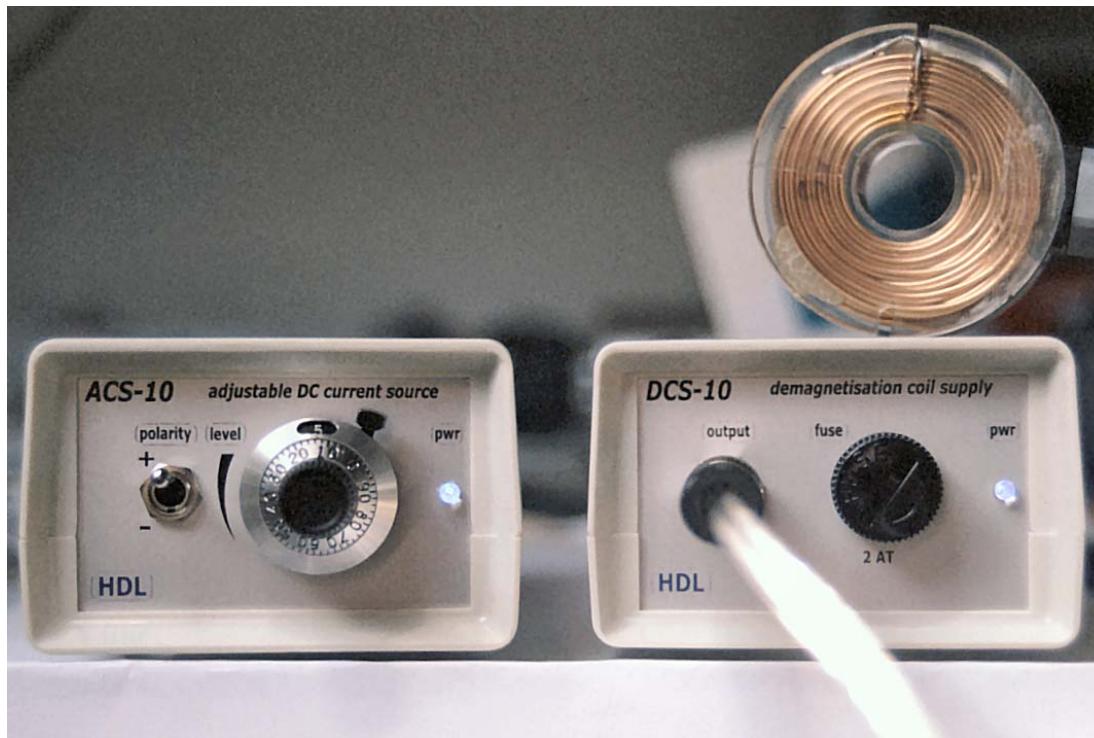
# Residual field measurement and compensation



$T_c$  of  $\text{AuAl}_2$  versus  $I_{comp}$  of SRD004, as measured by PTB.

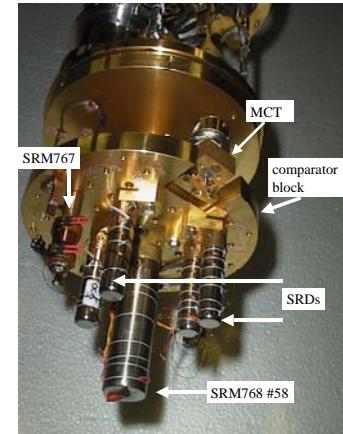
# Residual field measurement and compensation

- ACS-10 adjustable DC current source
- Optional input on MIDS-10 preamp for compensation field in X,Y plane
- DCS-10 degauss tool for the Cryoperm shield



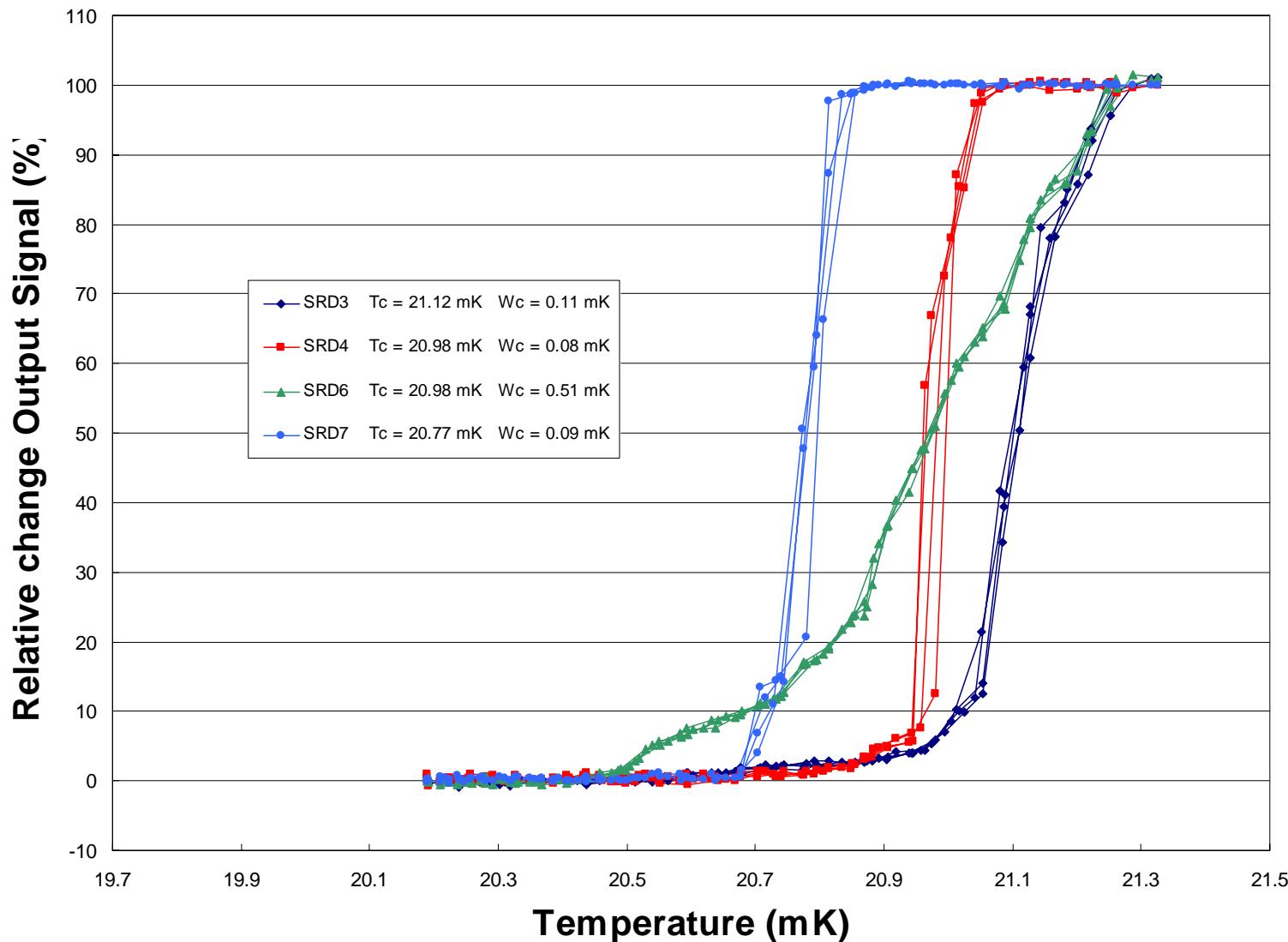
# Calibration of prototypes at NMi-VSL

- run 10 (June 2002): SRD003 / 004 / 005
  - SRD003 / 004: new samples and detectors required
  - SRD005: sent to BNM-INM for evaluation
  
- run 11 (October 2002): SRD003 / 004 / 006 / 007
  - $T_{\text{base}} > 16 \text{ mK}$ , no W calibration possible
  - occasionally the MCT blocks
  - temperature stabilisation problematic around 1 K
  - RhFe thermometer is not working properly
  - SRD003:  $\text{AuAl}_2$  is not visible, repair detector before evaluation
  - SRD004: sent to PTB for evaluation
  - SRD006/007:  $\text{AuIn}_2$  has long tail, new sample before evaluation



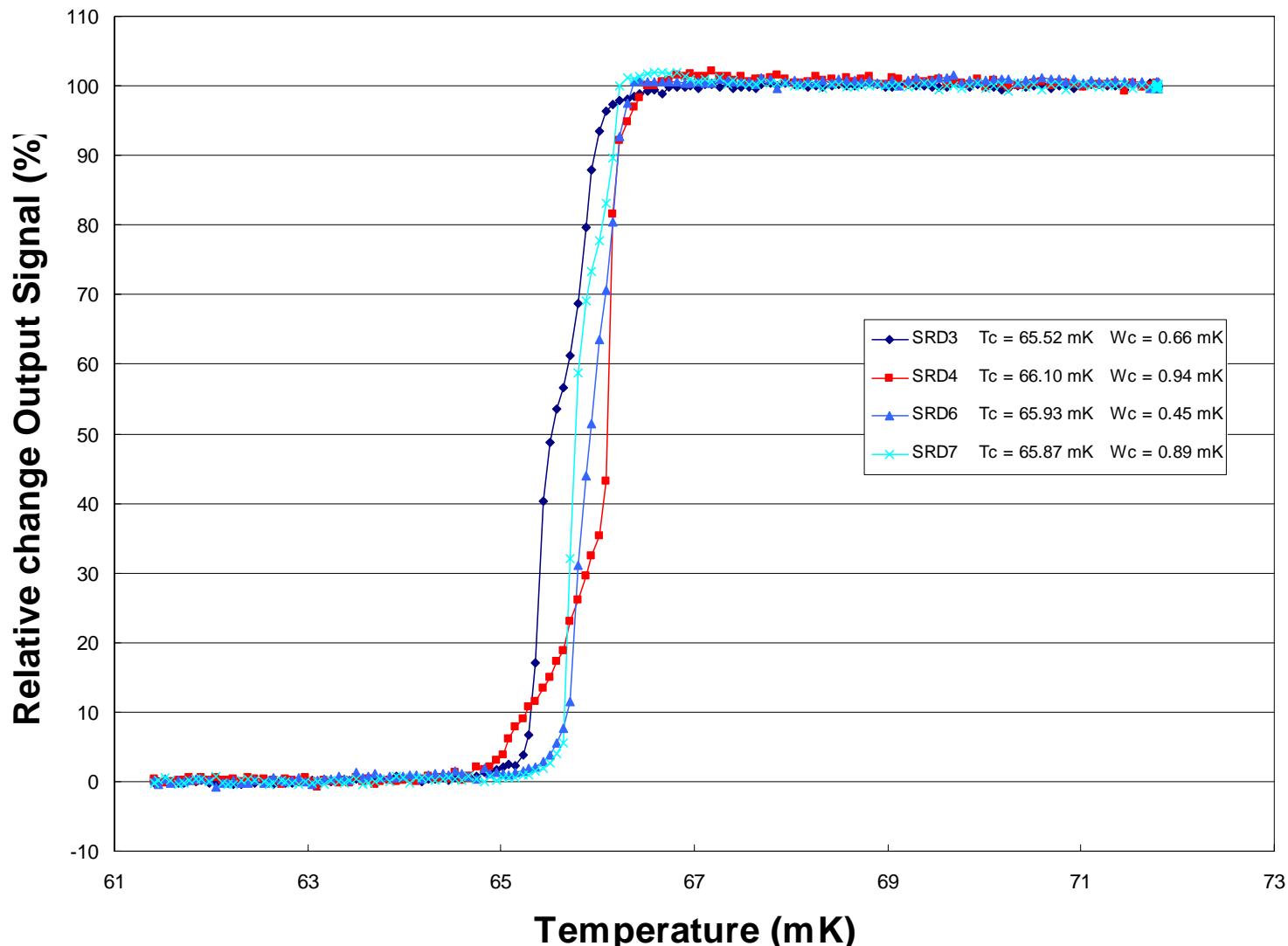
# Calibration of prototypes at NMi-VSL

## Berillium (run 11)



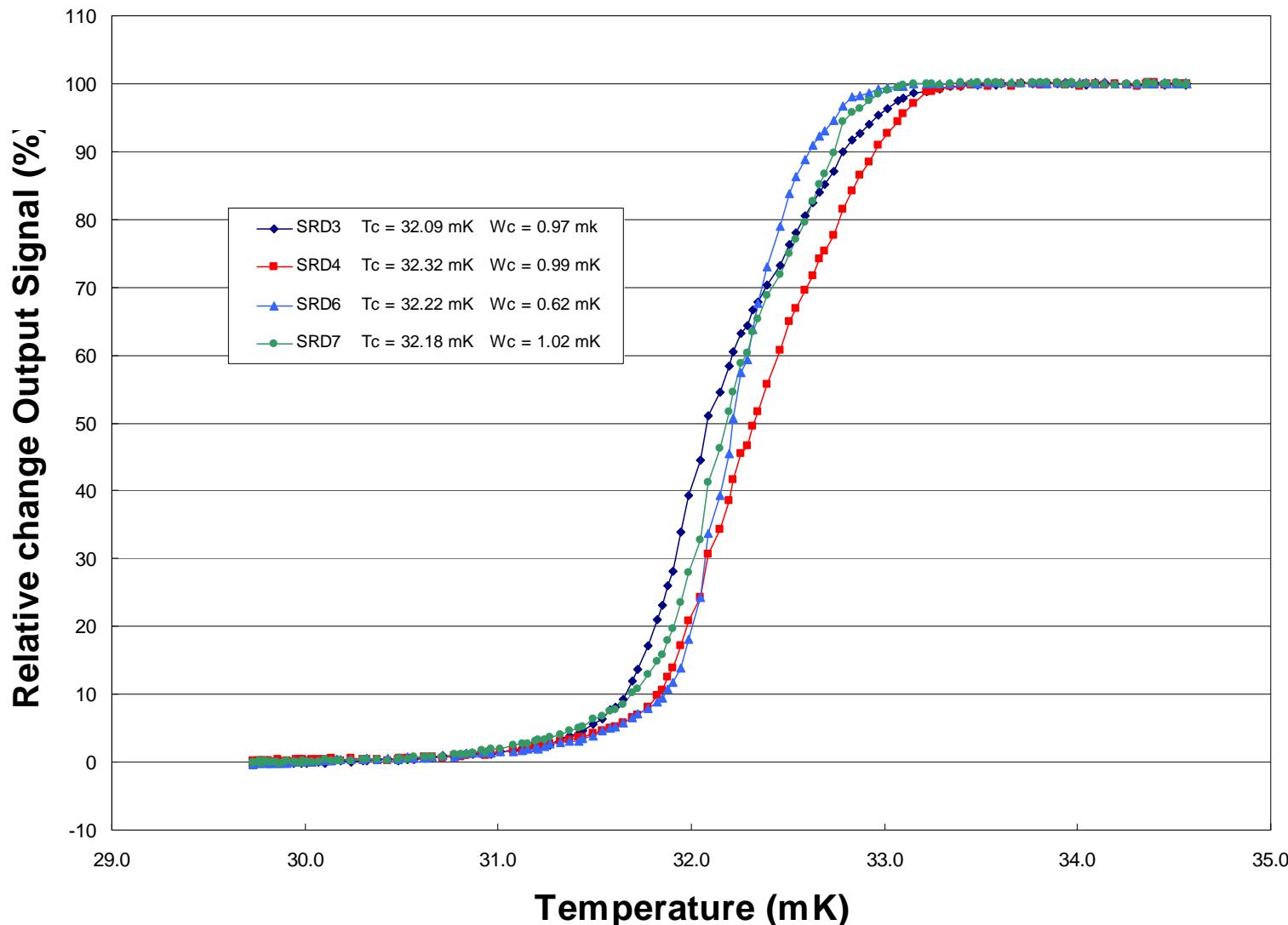
## Calibration of prototypes at NMi-VSL

Ir92Rh08 (run 11)



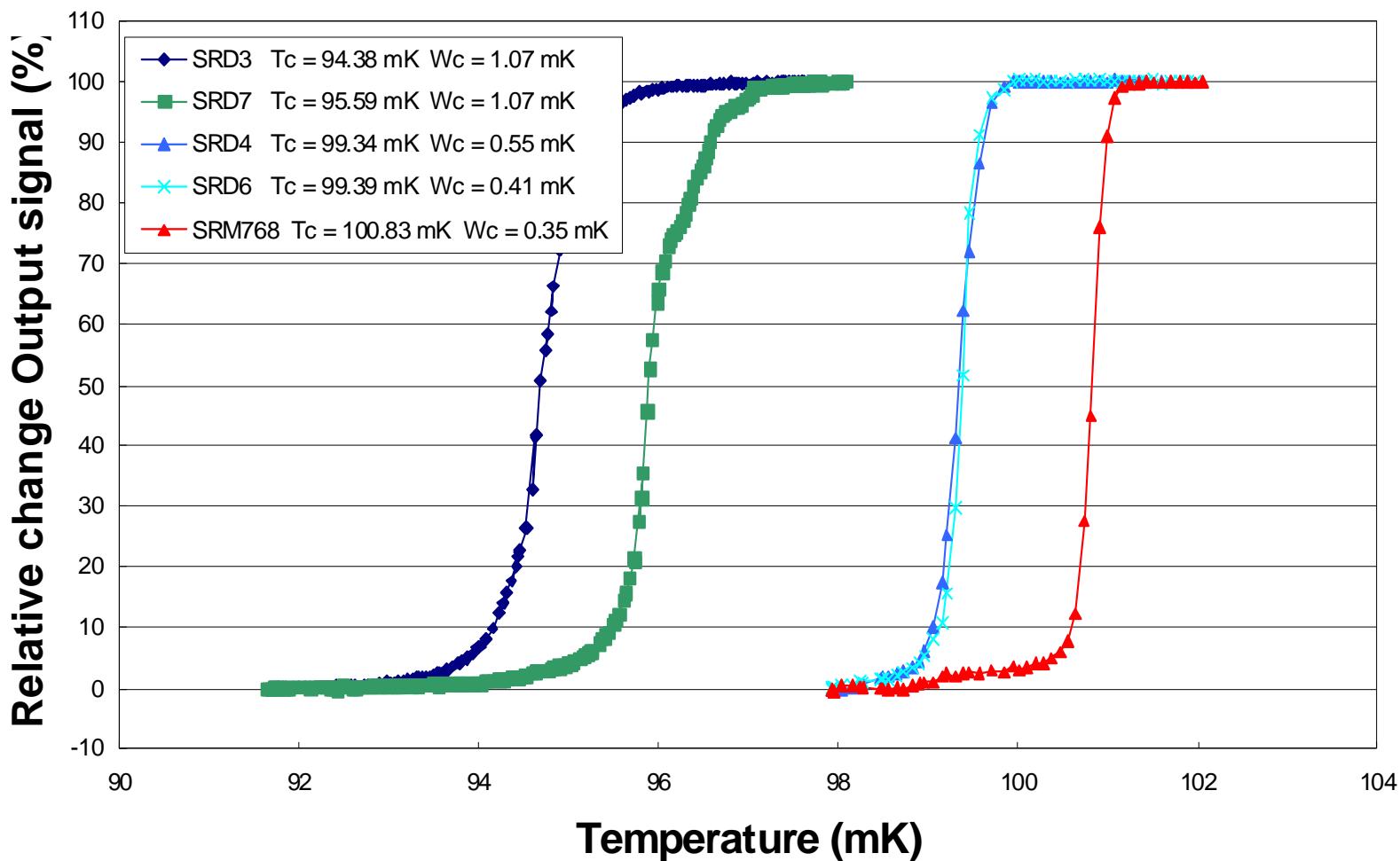
# Calibration of prototypes at NMi-VSL

## Ir80Rh20 (run 11)



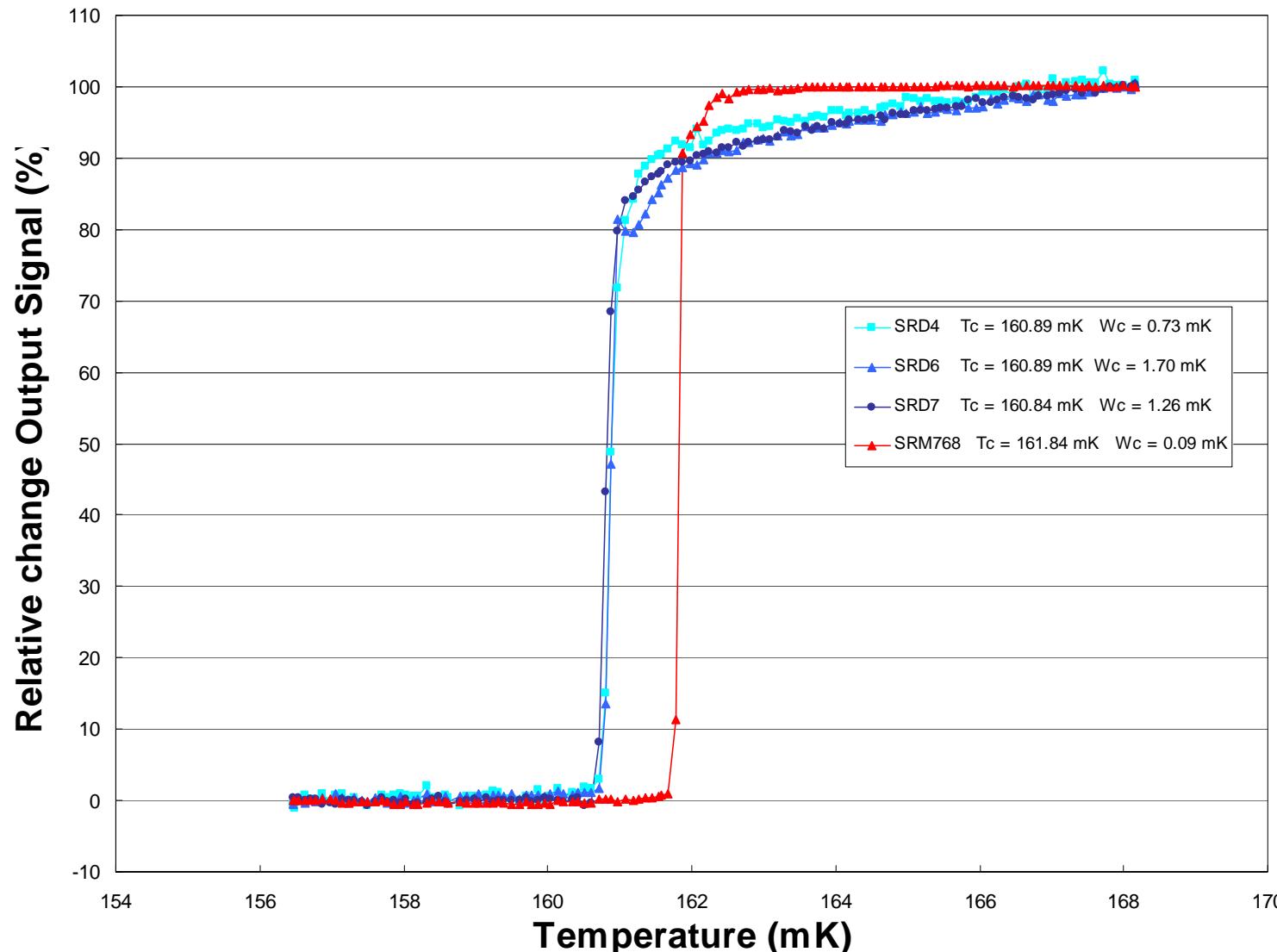
## Calibration of prototypes at NMi-VSL

## Iridium (run 11)



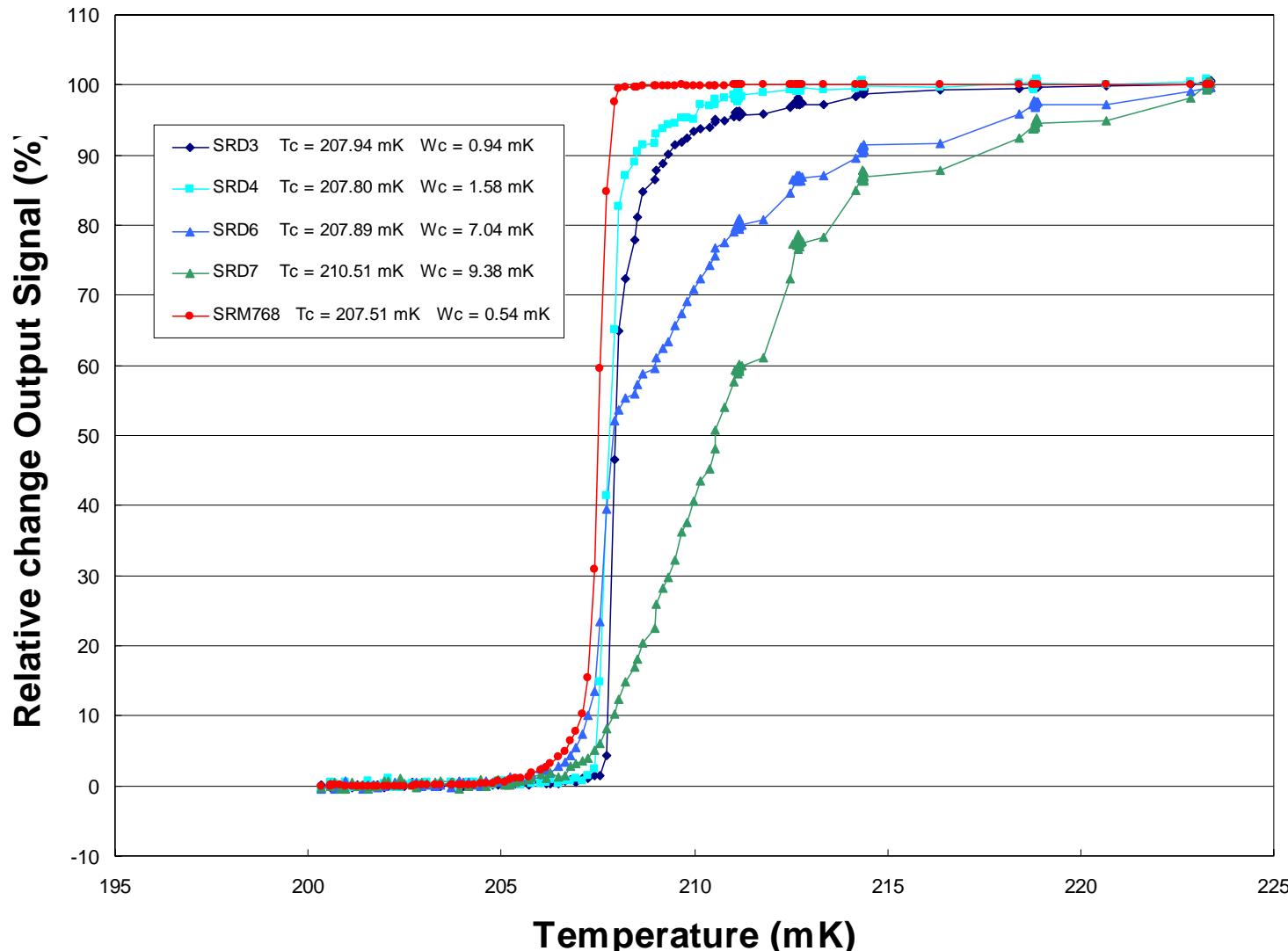
# Calibration of prototypes at NMi-VSL

## AuAl2 (run 11)



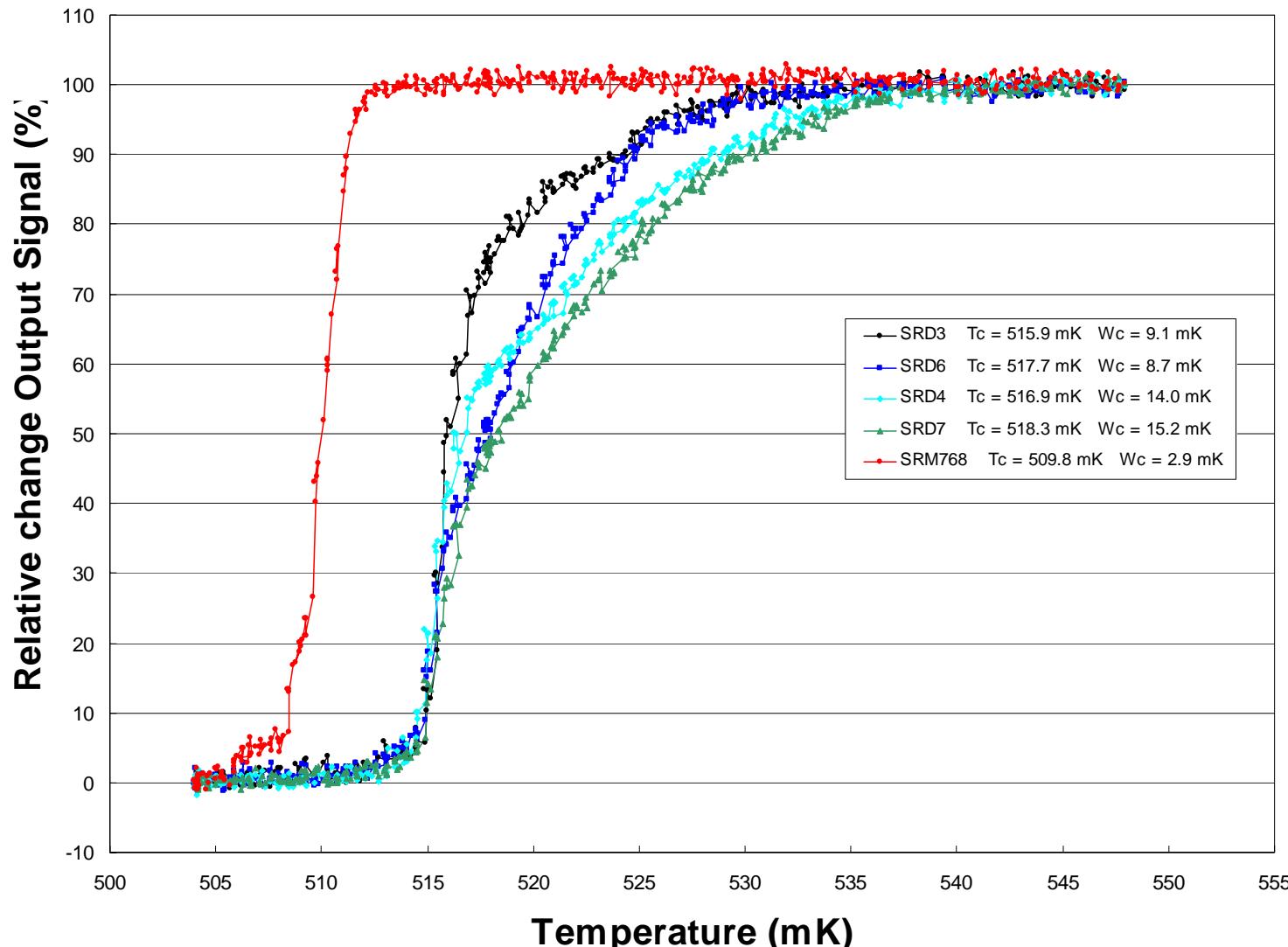
## Calibration of prototypes at NMi-VSL

Auln2 (run 11)



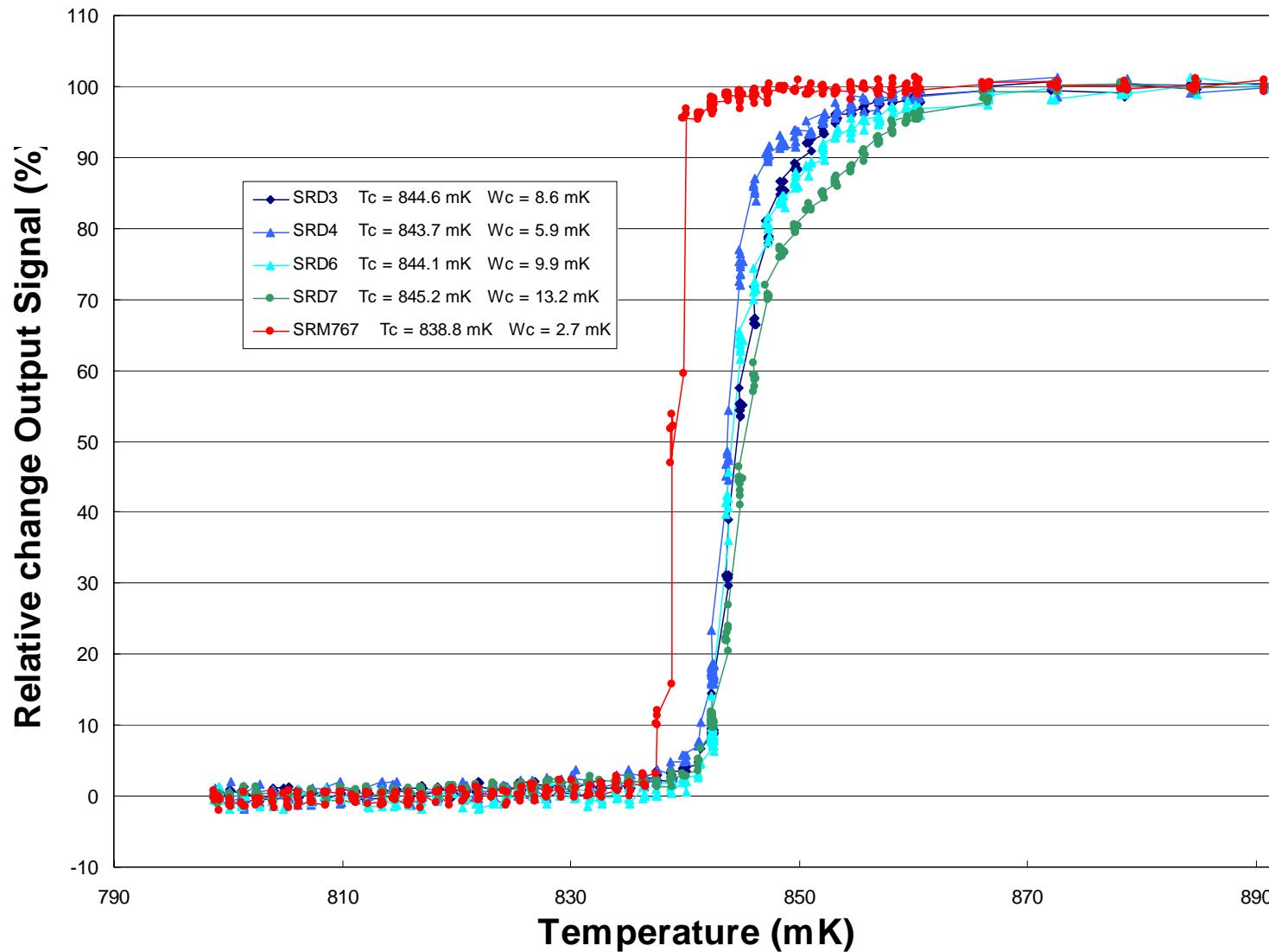
## Calibration of prototypes at NMi-VSL

## Cadmium (run 11)



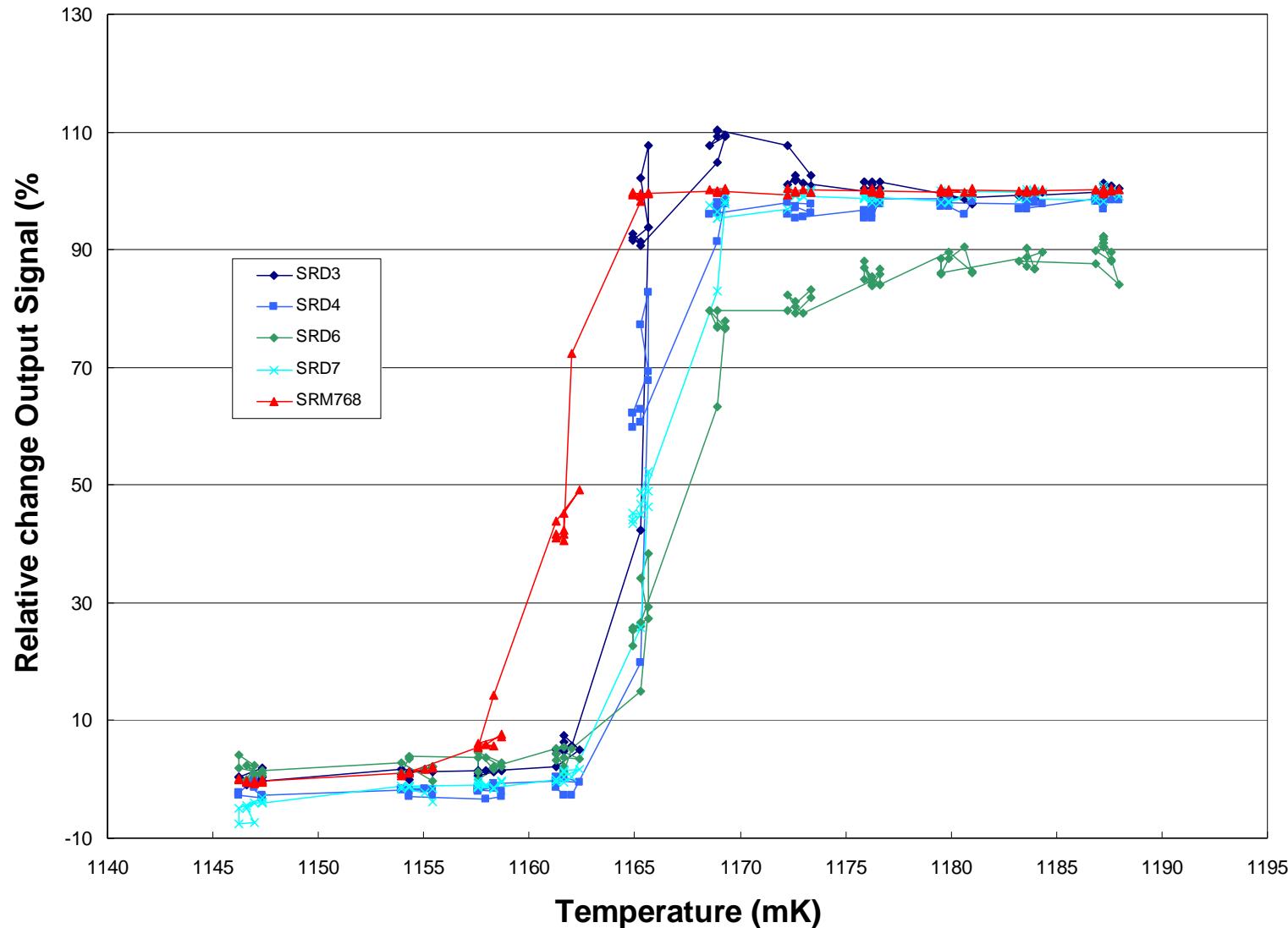
## Calibration of prototypes at NMi-VSL

Zinc (run 11)



# Calibration of prototypes at NMi-VSL

## Aluminium (run 11)



## Improvements to samples after run 11

$\text{AuAl}_2$  - annealing, pretest samples before mounting in prototypes  
- new samples were mounted in SRD003 and SRD006

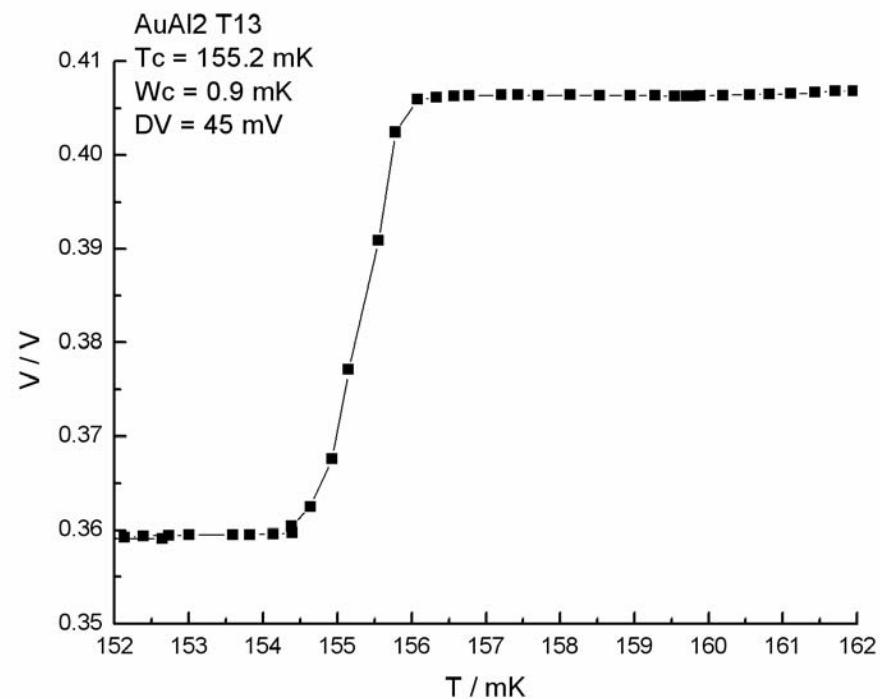
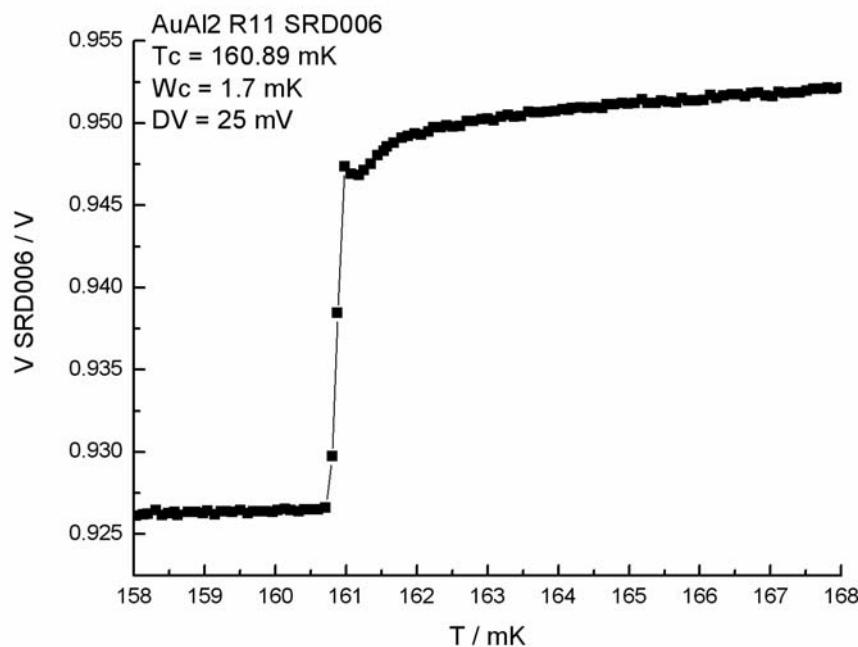
$\text{AuIn}_2$  - other batch produces better samples, pretest samples  
- new sample was mounted in SRD006

Cd - etching the surface reduces  $W_c$  by factor 3

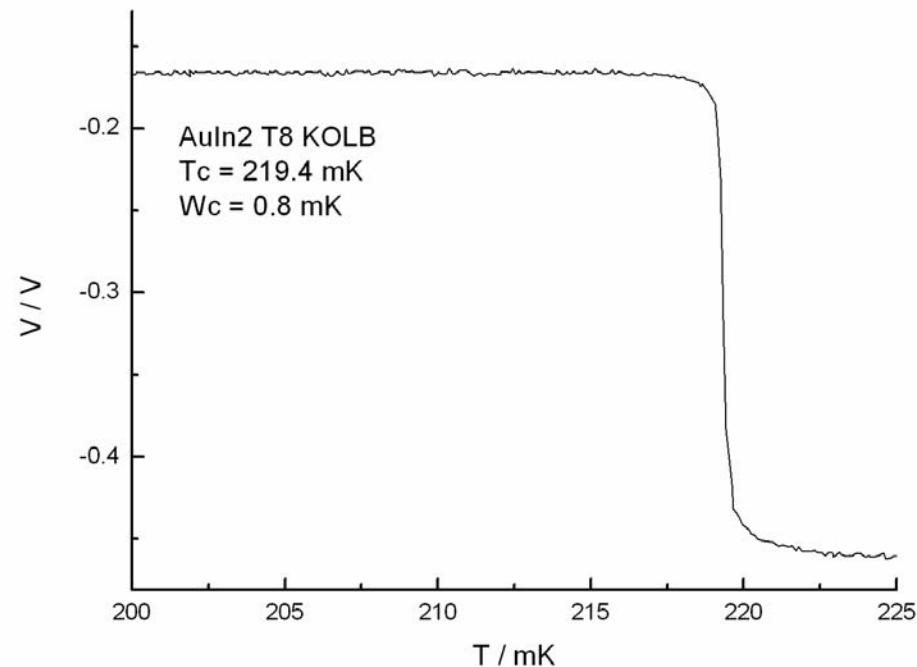
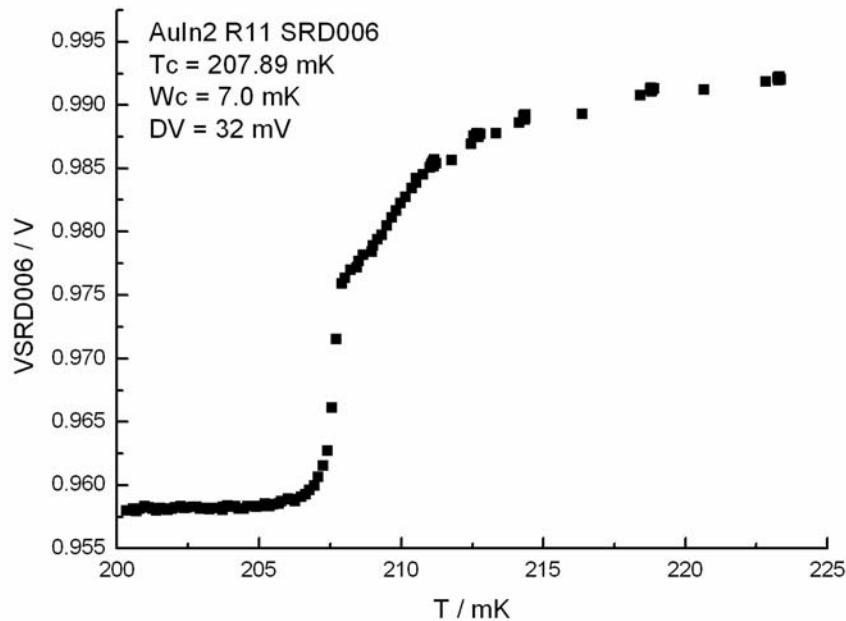
Zn - etching gives no improvement

Al - annealed wire replaces foil to reduce upturn effect bond wires  
- new samples were mounted in SRD003 and SRD006

## Improvements to samples after run 11

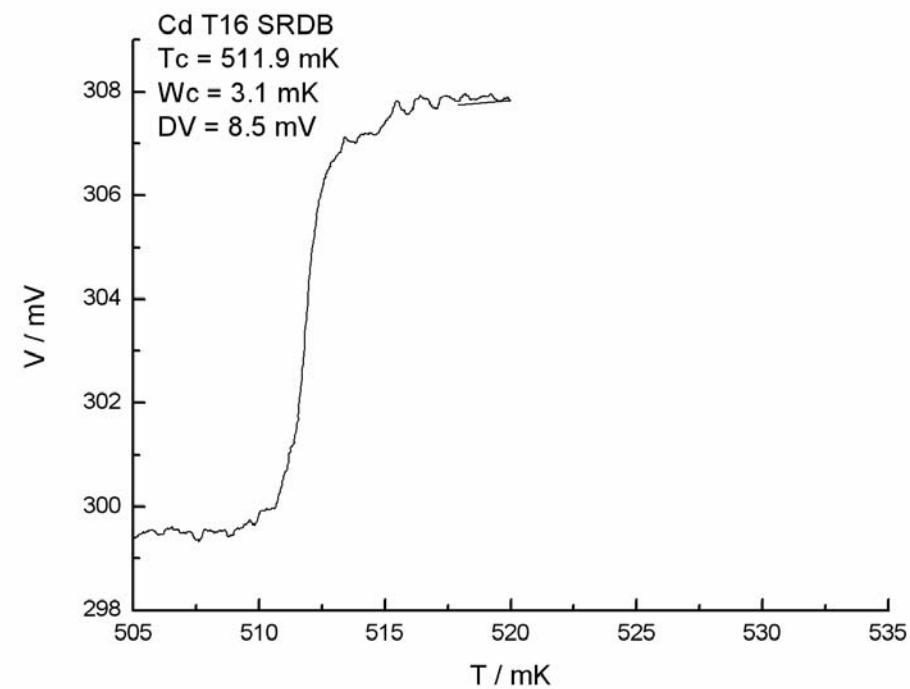
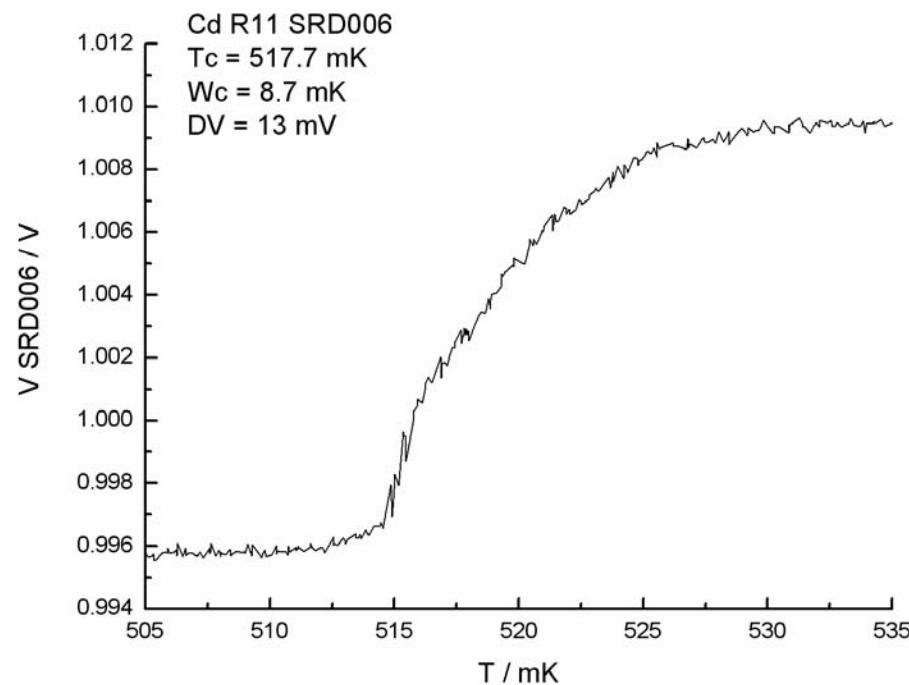
 $\text{AuAl}_2$ 

## Improvements to samples after run 11

**AuIn<sub>2</sub>**

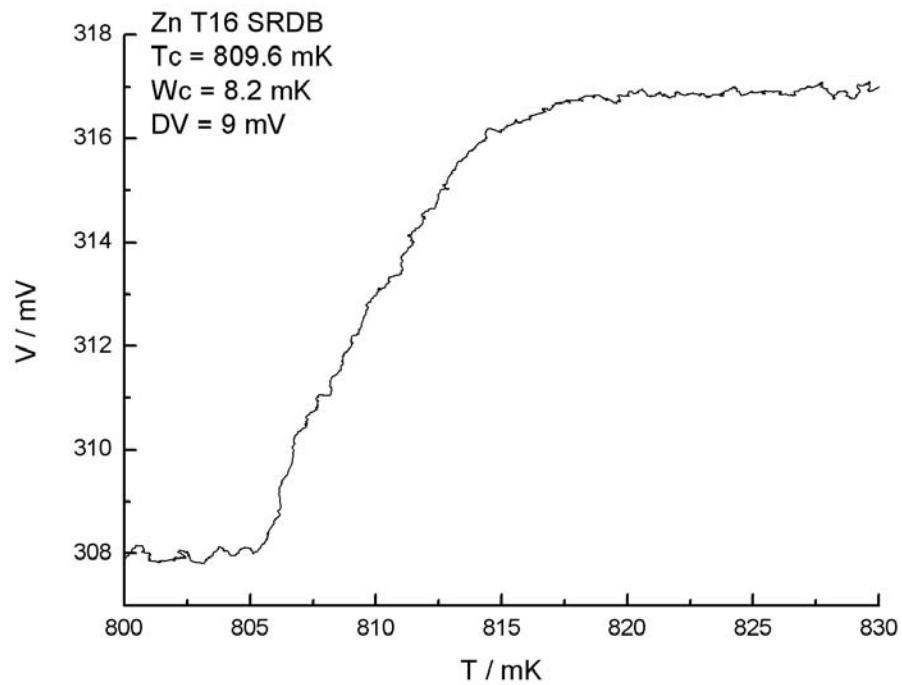
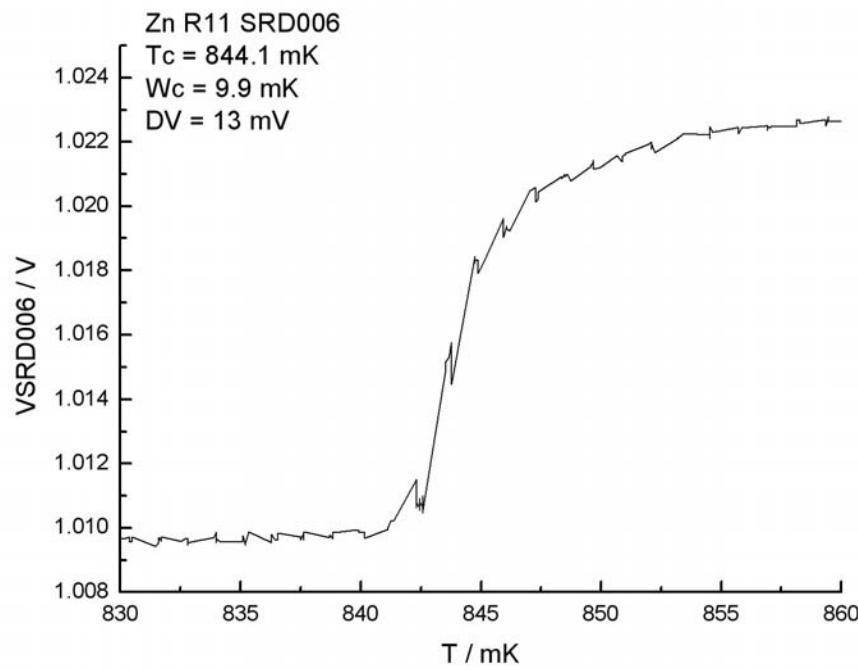
# Improvements to samples after run 11

## Cd



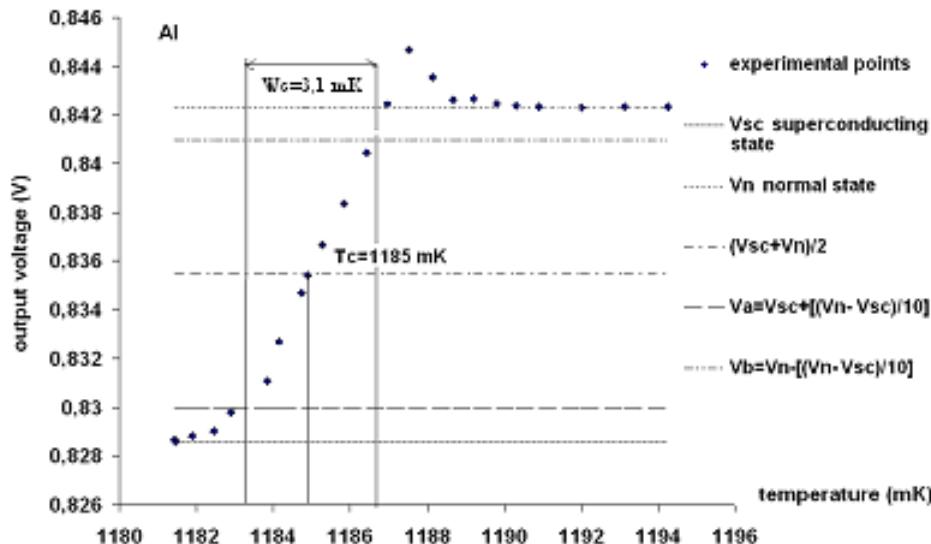
# Improvements to samples after run 11

## Zn

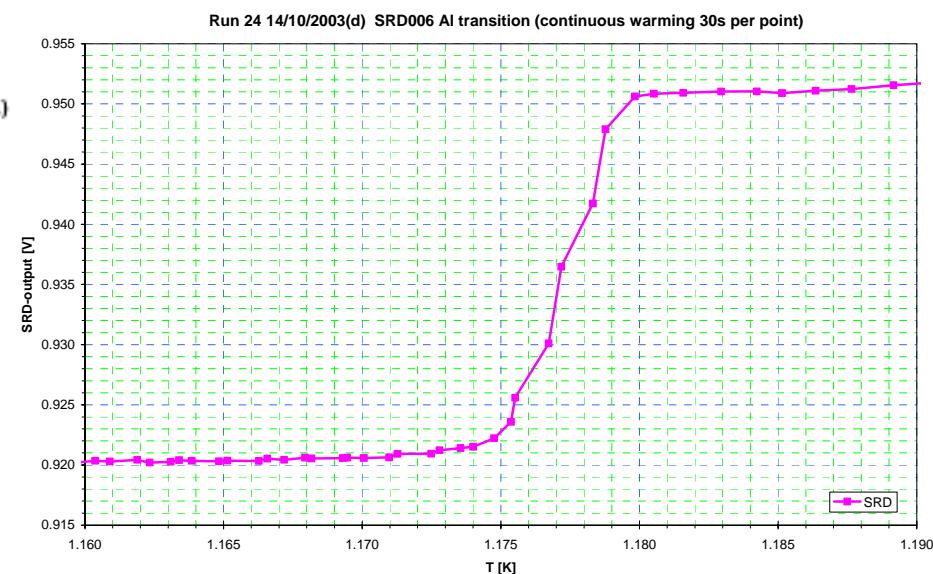


# Improvements to samples after run 11

## AI



SRD005 / BNM



SRD006 / NPL

# Evaluation of prototypes

#	calibration	samples modified	evaluation	status
SRD003	run 11	AuAl <sub>2</sub> , Al	CNRS / AL	in progress
SRD004	run 11	-	PTB	report ready
SRD005	run 10	-	BNM-INM	report ready
SRD006	run 11	AuIn <sub>2</sub> , AuAl <sub>2</sub> , Al	NPL	in progress



# Recent reports, posters, manuals, presentations

## 2003

- Peruzzi, A., de Groot, M.J. , "Evaluation of Uncertainty in the Realization of the Provisional Low Temperature Scale from 10 mK to 1 K at Nmi" in *Proceedings of the International Conference on the Uncertainty of Measurement UNCERT 2003*;
- SRD partners, 'Report on the development of SRD technology', May 2003, project deliverable 2.1;
- HDL, 'Information on the installation of an SRD1000 device in a dilution refrigerator', June 2003;
- HDL, 'Procedure to degauss the SRD1000 Cryoperm shielding using the DCS-10', June 2003;
- HDL, 'Checking the residual magnetic field inside the SRD1000 shielding at low temperatures using the ACS10', June 2003;
- Peruzzi, A., Bosch, W.A., 'Procedure for the Evaluation of SRD1000 prototypes', July 2003;
- Presentation by Andrea Peruzzi at the Wroclaw Low Temperature Thermometry seminar, October 2003;
- Presentation by Andrea Peruzzi at Estec / ESA Noordwijk, December 2003.

## 2002

- Bosch, W.A., et al. , "First Prototypes of the Superconductive Reference Device SRD1000", in *Proceedings of the 8<sup>th</sup> Symposium on Temperature: Its Measurement and Control in Science and Industry*, Chicago, 2002;
- Bosch, W.A., et al., "SRD1000: a Superconductive Reference Device for thermometry below 1K", poster presented at the LT23 conference Japan, 2002, and *Physica B*, 329-333 (2003), pp. 1562-1563.

## 2004 actions

- Reports: evaluation, TIP, final
- Market developmet
- Resources for calibrations
- Pilot series (5 - 10 devices)
- SRD technology
  - Improve sample quality, additional batches ( $\text{Ir} / \text{Ir}_x\text{Rh}_y$ )
  - Mo single crystal ( $T_c = 900$  mK) to replace Zn / Al
  - Ti layer with  $T_c = 300$  mK
  - Include thermometer for interpolation (CMN / PdFe / AuEr)